## Application/Control No. 10/042,846 Applicant(s)/Patent Under Reexamination HAIMOVSKY ET AL. Examiner Tse Chen Applicant(s)/Patent Under Reexamination HAIMOVSKY ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*	*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,948,101	09-1999	David et al.	713/2
	В	US-			
	C.	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
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## FOREIGN PATENT DOCUMENTS

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## NON-PATENT DOCUMENTS

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